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Secondary Ion Mass Spectrometry of Molecular Solids

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Table I

compd	conditions	hexenes		
 1	0 °C, thermal ^a	47	49	4.0
	-10 °C, thermal ^a	53	44	3.5
	-20 °C, thermal ^a	59	39	2.0
	-78 °C, $h\nu$ (direct) ^a	54	44	2.0
	-78 °C, $h\nu$ (sens) ^a	74	24	2.0
 7	140 °C, thermal ^b	52	46	2.0
	-78 °C, $h\nu$ (direct) ^a	56	42	2.0
	-78 °C, $h\nu$ (sens) ^c	72	26	2.0

^a CFC1₃. ^b Benzene. ^c CH₂Cl₂.

absorption spectrum is $1.3 \times 10^5 \text{ s}^{-1}$.⁸

For photochemical studies, the degassed chromatographed solution of **1** (~0.03 M in CFC1₃) was irradiated at 466–610 nm at -78 °C.⁹ After 12 h of irradiation at -78 °C the red color

Direct

had completely disappeared. Vapor-phase chromatography¹⁰ and ¹H NMR spectroscopy reveal four hydrocarbon products **2–5** and tetrazene **6** in a 1:4 ratio. Controls show that 0.03 M solutions of the 1,1-diazenes in CFC1₃ at -78 °C are stable.

The four hydrocarbon products **2–5** appear to be products from the photochemical extrusion of molecular nitrogen from **1**. The details of the mechanism for the loss of nitrogen are as yet unknown, but the products are the same as found in the thermal decomposition of **1**. The tetrazene **6**, an unexpected photoproduct, probably results from the bimolecular reaction of S₁ and/or T₁ with S₀.

Triplet sensitization experiments were carried out at longer wavelengths at -78 °C. Irradiation of degassed chromatographed solutions of **1** (0.03 M in CFC1₃) at >608 nm¹¹ in the presence of 0.02–0.05 M azulene sensitizer ($E_T = 31 \text{ kcal}$),¹² where the 1,1-diazenes was shown to be unreactive on direct irradiation, affords four hydrocarbon products **2–5** and tetrazene **6** in a 1:9 ratio. The product compositions from the thermal, direct irradiation and sensitized decompositions of **1** and the 1,2-diazenes isomer **7**^{13,15} are summarized in Table I.

The 2-methylpropene/tetramethylcyclobutane ratios for the direct and sensitized photodecomposition of the 1,1-diazenes **1** are

(8) Turro, N. J. "Modern Molecular Photochemistry"; Benjamin/Cummings: Menlo Park, CA, 1978.

(9) Irradiation with 1000-W xenon lamp, Corning filters CS3-70, and CS4-96.

(10) Hydrocarbon products were analyzed by analytical VPC (Carbowax 400, 25 °C) and compared with authentic samples. Tetrazene/hydrocarbon ratios were determined by NMR spectroscopy.

(11) Irradiated with 1000-W xenon lamp, Corning filter CS-2-59.

(12) Murov, S. "Handbook of Photochemistry"; Marcel Dekker: New York, 1973.

(13) 3,3,6,6-Tetramethyl-1,2-diazacyclohexene (**7**) was synthesized by the method of Greene.¹⁴

(14) Greene, F. D.; Gilbert, K. E. *J. Org. Chem.* **1975**, *40*, 1409

(15) Direct and triplet irradiation with 1000-W xenon lamp, Schott filter WG-335. The 1,2-diazenes **7** has been shown to be effectively triplet sensitized by thioxanthone.¹⁶

(16) Porter, N. A. Ph.D. Thesis, Harvard University, Cambridge, MA 1969.

1.14 and 3.08, respectively. Importantly, the 2-methylpropene/tetramethylcyclobutane ratios are the same from the 1,1- and 1,2-diazenes isomers in the direct and sensitized photolyses. Common singlet and triplet 1,4-biradicals formed from loss of nitrogen from S₁ and T₁, respectively, from **1** and **7** would be sufficient to explain these results. Bartlett and Porter have shown a spin correlation effect on the product ratios in the direct and triplet sensitized photodecomposition of cyclic 1,2-diazene isomers similar to **7**.^{17,18} Because the hydrocarbon product ratios from **1** are different for direct vs. sensitized photolyses, but in agreement with the product ratios from the 1,2-diazenes isomer **7**, this may indicate a spin correlation effect in the 1,1-diazenes case. This apparent lack of significant intersystem crossing would be consistent with the large calculated S₁–T₁ gap in the 1,1-diazenes.^{1f} Control experiments show that the 1,1-diazenes **1** does not rearrange (<1%) to the more stable 1,2-isomer **7** under direct or sensitized photolysis.¹⁹

In summary, evidence has been provided that S₁ of the 1,1-diazenes **1** is deactivated at least in part by fluorescence, loss of nitrogen, and tetrazene formation. Similarly, T₁ is deactivated in part by loss of nitrogen and tetrazene formation. The appearance of tetrazene **6** on direct irradiation is significant because, in the absence of S₁ → T₁ intersystem crossing, one can estimate an upper limit of $\leq 7 \times 10^7 \text{ s}^{-1}$ ²⁰ on the unimolecular rate for loss of N₂ from S₁. Issues that are currently under investigation include a direct measurement of the lifetime of S₁, a stereochemical test to quantitate the apparent spin correlation effect and a search for triplet emission which would locate the S₀–T₁ gap in the 1,1-diazenes.

Acknowledgment. We are grateful to the National Science Foundation (CHE80-06495) for support of this research.

(17) Bartlett, P. D.; Porter, N. A. *J. Am. Chem. Soc.* **1968**, *90*, 5317.

(18) For an excellent discussion and review of spin correlation effects in 1,2-diazene isomers, see: Engel, P. S. *Chem. Rev.* **1980**, *80*, 99.

(19) However, we cannot rule out that photoexcited **1** rearranges to photoexcited **7** which then undergoes reaction.

(20) Assuming $k(S_1 + S_0) \leq 9.3 \times 10^9 \text{ M}^{-1} \text{ s}^{-1}$, concentration of S₀ ≤ 0.03 M, and ratio of hydrocarbons/tetrazene products = 0.25.

Secondary Ion Mass Spectrometry of Molecular Solids: A Source of Cluster Ions

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Secondary ion mass spectrometry (SIMS) shows considerable promise as a method for characterization of nonvolatile molecular solids.¹ The observed molecular ions and fragment ions are often accompanied by cluster ions. In the case of solid hydrocarbons (methane,² cyclohexane,³ benzene³), a rich variety of cluster ions is formed, but no repeating solvating unit is readily detected. On the other hand, several solids composed of small molecules yield cluster ions of regular composition [H⁺(H₂O)_n from ice,³ (N₂)_n⁺ and N(N₂)_n⁺ from solid nitrogen,^{2,4} C⁺(CO)_n, C₂⁺(CO)_n, and (CO)_n⁺ from solid CO,⁴ C⁺(CO₂)_n and (CO₂)_n⁺ from solid CO₂],

(1) R. J. Day, S. E. Unger, and R. G. Cooks, *Anal. Chem.*, **52**, 557–72A (1980); B. L. Garrison, *J. Am. Chem. Soc.*, **102**, 6553–6555 (1980); N. Winograd and B. L. Garrison, *Acc. Chem. Res.*, **13**, 406–412 (1980).

(2) H. T. Jonkman and J. Michl, *Springer Ser. Chem. Phys.*, **9**, 292–294 (1979).

(3) G. M. Lancaster, F. Honda, Y. Fukuda, and J. W. Rabalais, *J. Am. Chem. Soc.*, **101**, 1951–1958 (1979).

(4) H. T. Jonkman and J. Michl, *J. Am. Chem. Soc.*, **103**, 733–737 (1981).

Figure 1. Positive SIMS of solid NO with Ar⁺ at 4 keV.

leading one to believe that the solvating units will generally reflect the molecular component of solids composed of small molecules.

We now wish to report that SIMS of solid N₂O, NO, N₂O₃, N₂O₄, and O₂ produces strange clusters of readily characterized compositions in which the solvating unit is not simply related to the molecular composition of the solid. The measurements were performed as in ref 4, and the purity of the gases used was monitored carefully by mass spectrometry. The nature of the secondary ions was independent of the conditions of the experiment, but the relative abundance of heavy cluster ions was maximized by the use of heavy primary ions (Ar⁺, Kr⁺, Xe⁺) and higher primary ion energies (4 keV).

The SIMS of solid NO, shown in Figure 1, is dominated by the molecular ion. Fragment ions are nearly absent, as are the expected simple cluster ions (NO)_n⁺. The dominant cluster ions have the composition [NO(N₂O₃)_n]⁺ up to the limit *n* = 11, imposed by our mass spectrometer. The series [N₂O(N₂O₃)_n]⁺, [NO₂(N₂O₃)_n]⁺, and [N(N₂O₃)_n]⁺ are observed much more weakly. The solvating unit, N₂O₃, is richer in oxygen than the molecules of the solid itself.

The SIMS of solid N₂O, N₂O₃, and N₂O₄ are distinctly different (Figure 2). The base peak is again NO⁺, and other fragment ions and the molecular ion are seen only very weakly. A prominent series of clusters, [NO(N₂O₃)_n(N₂O₄)_m]⁺, is observed to the instrumental limit. The relative abundance of the N₂O₄ solvating units increases in the order solid NO, N₂O₃, N₂O, and N₂O₄. It is noteworthy that the oxygen-rich solvating unit, N₂O₄, is so prominent in the solid with the oxygen-poor stoichiometry, N₂O. For solid N₂O₄, cluster ions [NO(N₂O₄)_n(N₂O₃)_m]⁺, *n* = 1, 2, are also observed.

The SIMS of solid O₂ is dominated by the peaks of O⁺ and O₂⁺, while O₃⁺ is hardly observable. Clusters are again observed to the instrumental limit. The strongest series is O_{3n+2}⁺, suggesting O₃ as the primary solvating unit.

The strange selectivity with which larger solvating units such as N₂O₃, N₂O₄, and O₃ are associated with a central positive ion in spite of the excess of the molecules of the solid, such as NO, N₂O, or O₂, present at first, suggests the initial formation of reactive charged and neutral fragments (O, N, O⁺, etc.), which then react to produce N₂O₃, N₂O₄, or O₃ units, either before or after the separation of a piece of the molecular solid carrying a positive charge from the bulk solid. The warmed-up cluster will then shake off its least firmly held components, leaving the more polarizable larger solvating units observed. The feasibility of this is indicated by the report⁶ that clusters of type [NO(N₂O₃)_n]⁺ are formed upon electron impact on gaseous NO expanding from a nozzle, with an intensity distribution similar to that shown in Figure 1.

The chemical reactions involved can be compared to those occurring in high-pressure mass spectrometry and radiation chemistry.⁷ It is tempting to postulate that oxygen atoms play a crucial role for all five solids. In NO, one expects processes such

Figure 2. Positive SIMS of solid N₂O, N₂O₃, and N₂O₄ with Ar⁺ at 3 keV (~18 K). The dots indicate the positions of intense peaks in the SIMS of solid NO.

as N + NO → N₂ + O, O + NO → NO₂, and NO₂ + NO → N₂O₃. In N₂O, the expected processes are N + N₂O → N₂ + NO, O + N₂O → 2NO or N₂ + O₂, O + NO → NO₂, NO₂ + NO → N₂O₃, and in N₂O₃, they are N + N₂O₃ → 3NO and O + N₂O₃ → N₂O₄. In N₂O₄, reactions such as N + N₂O₄ → NO + N₂O₃, NO + N₂O₄ → NO₂ + N₂O₃, and O + N₂O₄ → N₂O₅ appear probable. In many of these processes, the reactive species may actually be an ion rather than a neutral.

In the SIMS of solid NO, NO₂ is likely to be converted into N₂O₃ efficiently by the excess NO present. In the SIMS of solid N₂O, this conversion should be less efficient since NO is scarce, accounting for the observed presence of N₂O₄ in the clusters. In solid N₂O₄, NO should be trapped efficiently to produce N₂O₃, while O can yield N₂O₃. The abundance of N₂O₄ present is reflected in the composition of the clusters. In the SIMS of O₂, initially formed O atoms can be expected to add to O₂ to produce O₃.

All of these postulates are compatible with the observed negative SIMS of these solids, which shows mostly O⁻ ions. The most striking among these are the negative SIMS of N₂O₃ and N₂O₄ which show intense peaks for NO₃⁻, N₂O₆⁻, and N₃O₇⁻, and a series of higher clusters extending to the instrumental limit.

We conclude that even for solids composed of small molecules, cluster composition need not be indicative of the composition of the solid. The complexity of the processes suggested by the present results already for solids composed of very simple molecules has ominous connotations for attempts to analyze in detail the SIMS of neat organic solids. In analytical applications, it would appear essential to work under conditions of higher dilution (matrix isolation,^{2,8} surface adsorbate analysis^{1,9}).

Finally, we note that ion impact on low-temperature solids promises to provide a rich source of novel cluster ions.

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(5) R. G. Orth, H. T. Jonkman, and J. Michl, unpublished results.

(6) D. Golomb and R. E. Good, *J. Chem. Phys.*, **49**, 4176-4180 (1968).

(7) S. G. Lias and P. Ausloos, "Ion-Molecule Reactions. Their Role in Radiation Chemistry", American Chemical Society, Washington, D.C., 1975; K. Nishimura, O. Tokunaga, M. Washino, and N. Suzuki, *J. Nucl. Sci. Technol.*, **16**, 596-604 (1979), and references therein.

(8) H. T. Jonkman and J. Michl, *J. Chem. Soc., Chem. Commun.*, 751-752 (1978).

(9) A. Benninghoven, *Surf. Sci.*, **35**, 427-457 (1973); A. Benninghoven, Ed., *Springer Ser. Chem. Phys.*, **9**, 116-121 (1979).